

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

SEKIYA ET AL.

Examiner

Mark L. Berch

Art Unit

1624

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,734,187 B1	05-2004	Tanaka et al.	514/263.22
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

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